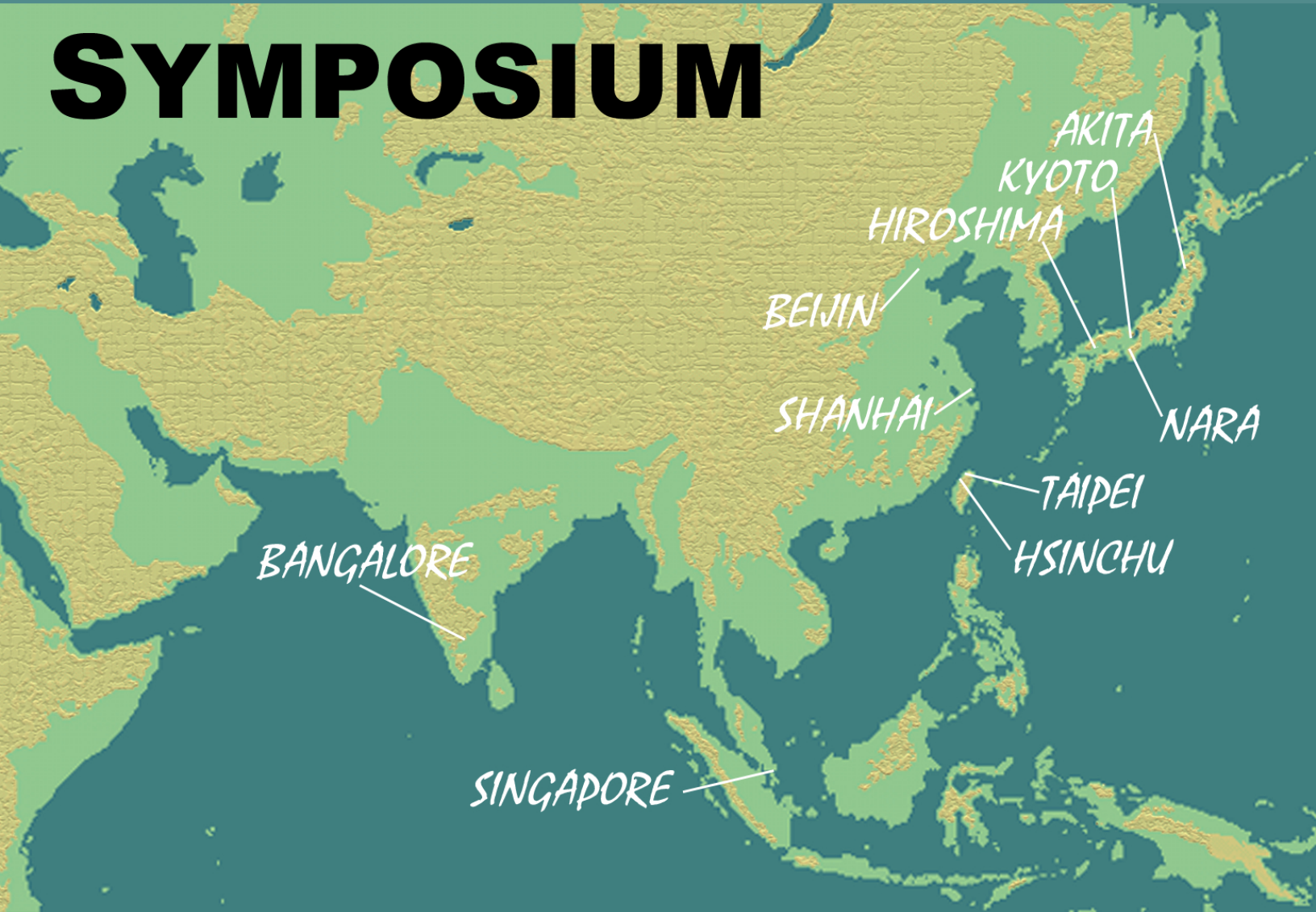


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- Test Set Partitioning and Dynamic Fault Dictionary for Sequential Circuits
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W- C. Wu, C-L.n Lee, and J- E. Chen
- GID--Testable Two-Dimensional Sequential Arrays for Self-Testing
W.K.Huang, F.Lombardi, and M.Lu
- A Global BIST Methodology
T.Gheewala, H.Sucar, and P.Varma
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- Analysis and Improvement of Testability Measure Approximation Algorithms
J. Bitner, J. Jain, J.A. Abraham, and D.S. Fussell
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A. Balakrishnan and S. T. Chakradhar
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K.-J. Lee, J.-J. Tang, T.-C. Huang, and C.-L. Tsai

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*Y. Huang, W. T. Cheng, C. C. Tsai, N. Mukherjee, O. Samman, Y.,
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